

2021 IEEE International Symposium on Defect and Fault Tolerance in VLSI and Nanotechnology Systems (DFT 2021)

**Virtual Conference
6 – 8 October 2021**



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34th IEEE International Symposium on
Defect and Fault Tolerance in VLSI and Nanotechnology Systems
Technical Program

(DFT 2021)

October 6-8, 2021

- ❖ The time is in CEST zone
- ❖ (L) stands for Long papers and (S) stands for Short papers
- ❖ The duration of the prerecorded presentations is 15 to 20 minutes. The duration of the live presentation of each paper is 15 minutes (5 to 7 minutes live talk and Q&A)

DAY 1 – Wednesday October 6, 2021

14:45 - 15:10: Starting Session

General Chairs' Welcome Message

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Organizer/Moderator: Ricardo Cantoro, Politecnico di Torino

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Paolo Bernardi (Politecnico di Torino, IT)

❖ Software-based self-test development and grading for an AI chip...N/A
L. Zaia (Dolphin Design, Fr)

❖ High-level Fault Injection for Reliability Assessment of Automotive Applications...N/A
G. Insinga (Xilinx Inc., US)

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Organizer/Moderator: Emanuele Valea (CEA-List, France)

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- ❖ Introduction to SIKE, plus related fault attack and countermeasure...N/A
Simon Pontié (CEA, France)
- ❖ Leveraging Inexact Computing in Post-Quantum Cryptography...N/A
François-Xavier Standaert (Université Catholique de Louvain)

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- ❖ Assessment of side-channel information leakage in cryptographic circuits...N/A
Sylvain Guilley (Secure-IC, France)

- ❖ Digital sensor dimensioning for mitigating aging-induced reliability concerns...N/A
Naghmeh Karimi (UMBC, USA)

18:35: Concluding Session